

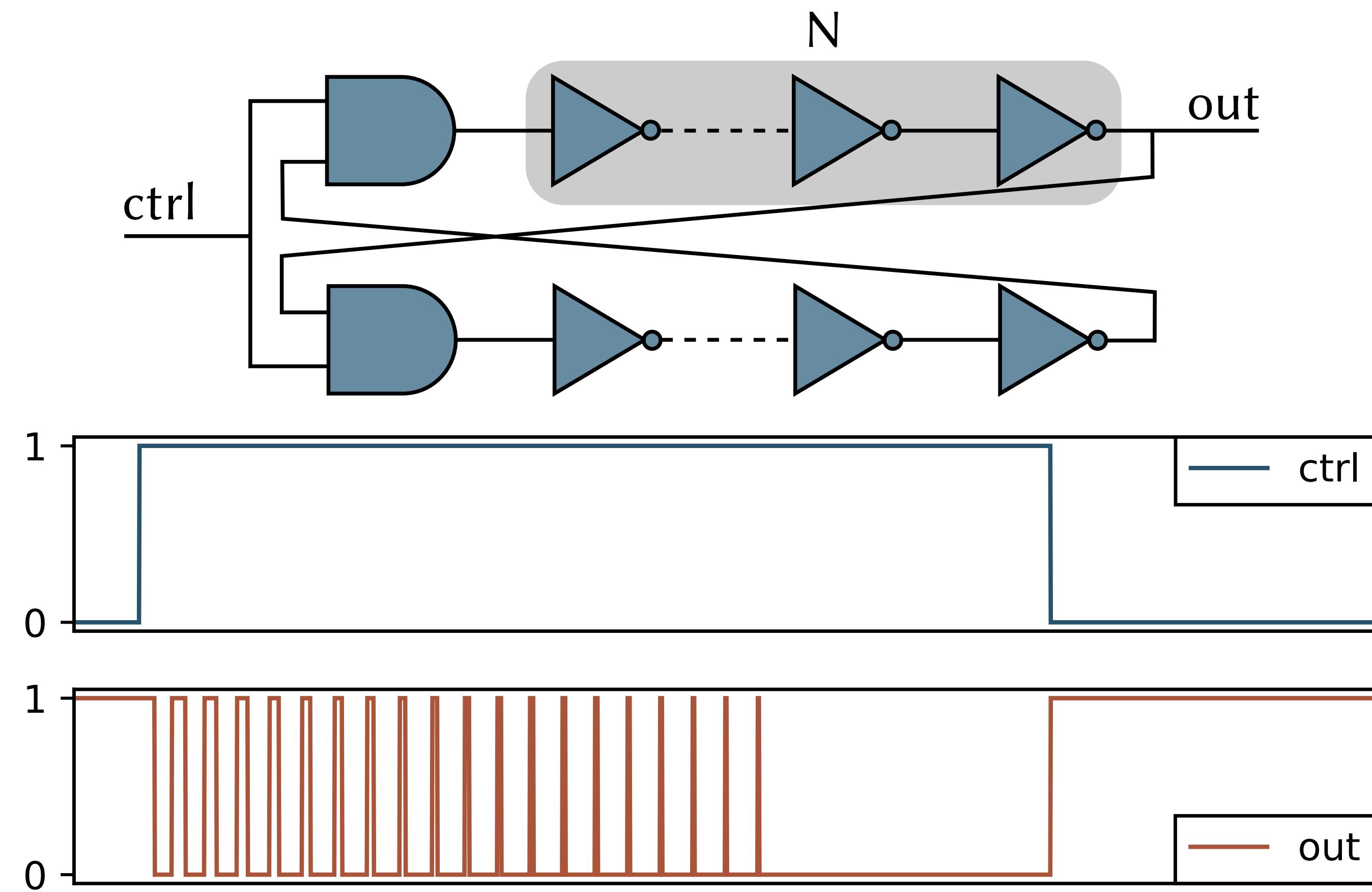
# Transient Effect Ring Oscillators Leak Too

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## Transient Effect Ring Oscillator

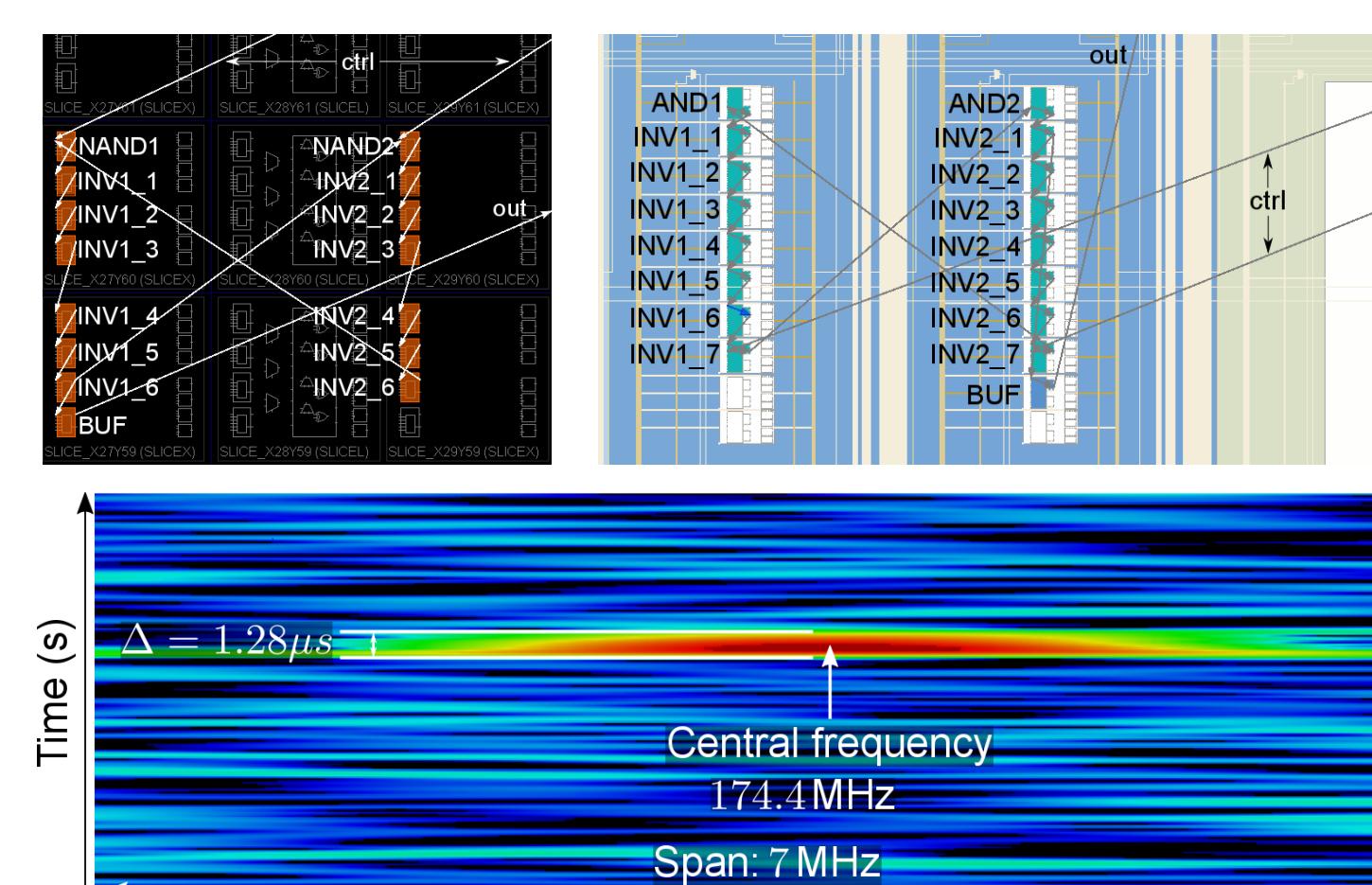


The **number of oscillations** is unique and depends on **manufacturing process variations**.

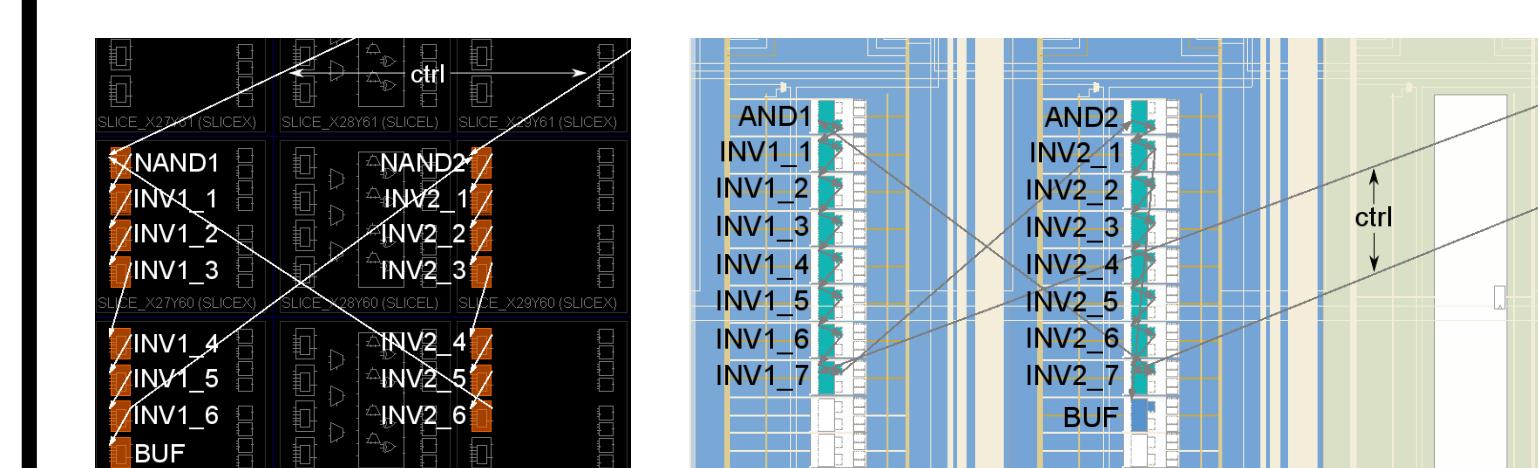
## Implementations and results

### One TERO + output buffer

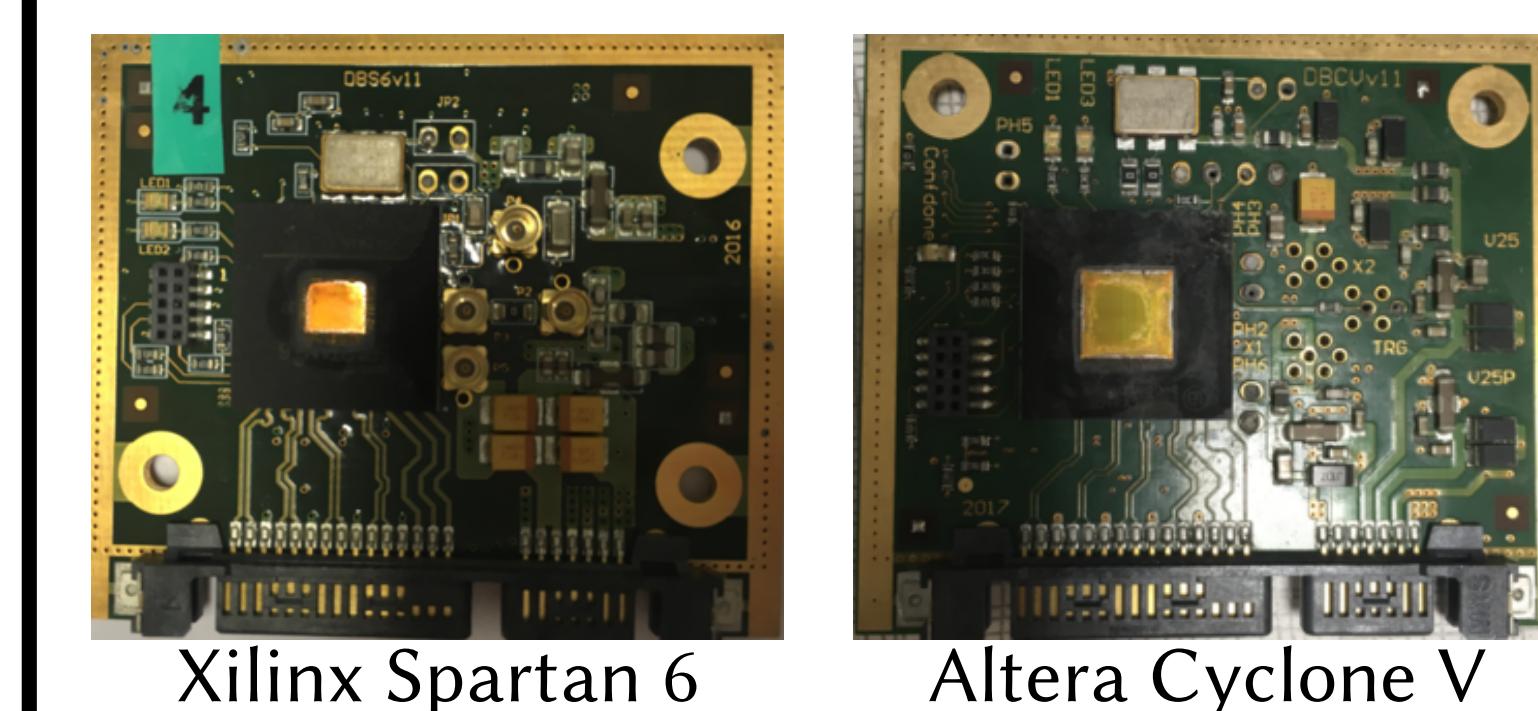
no decapsulation



### One TERO only

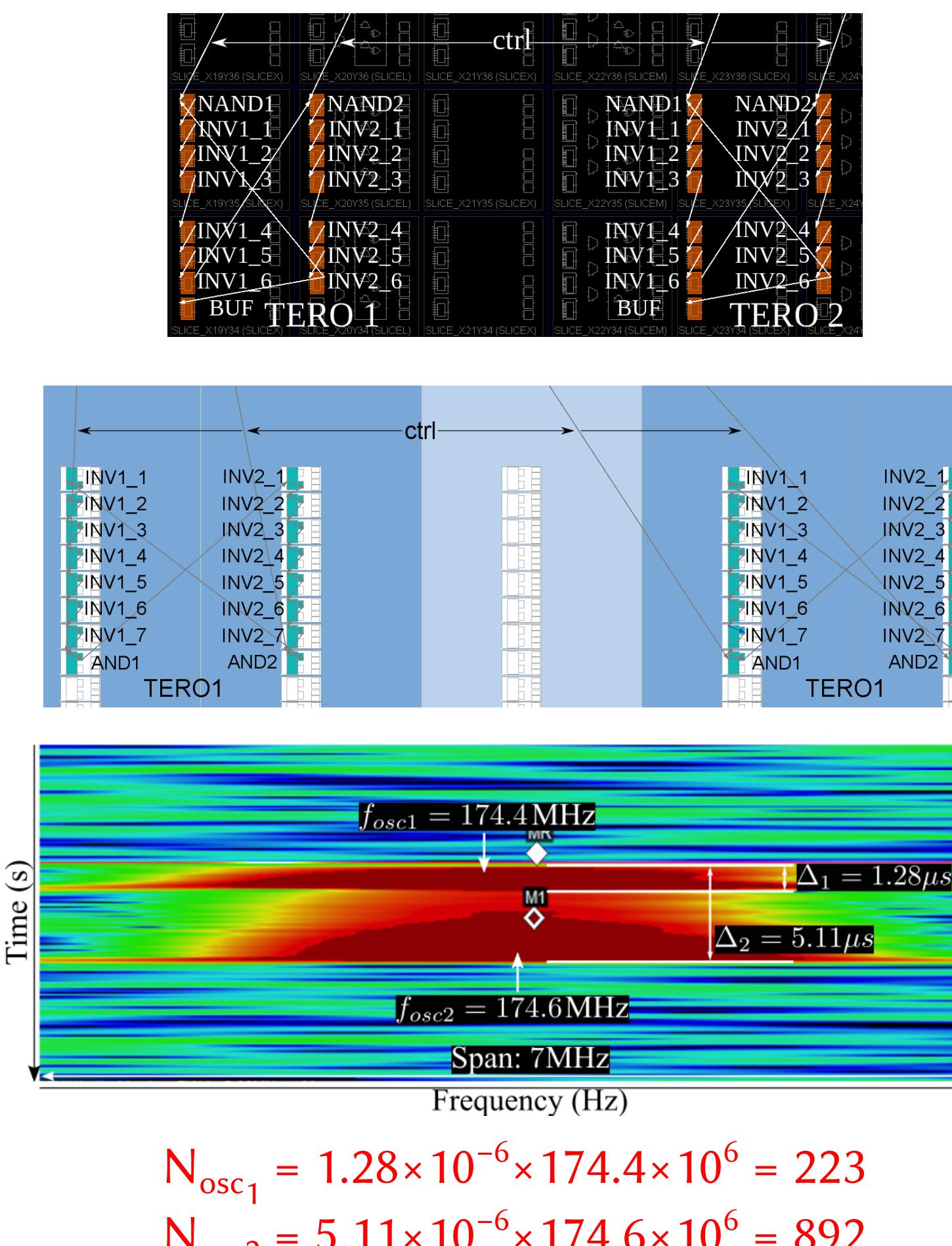


Decapsulation is required

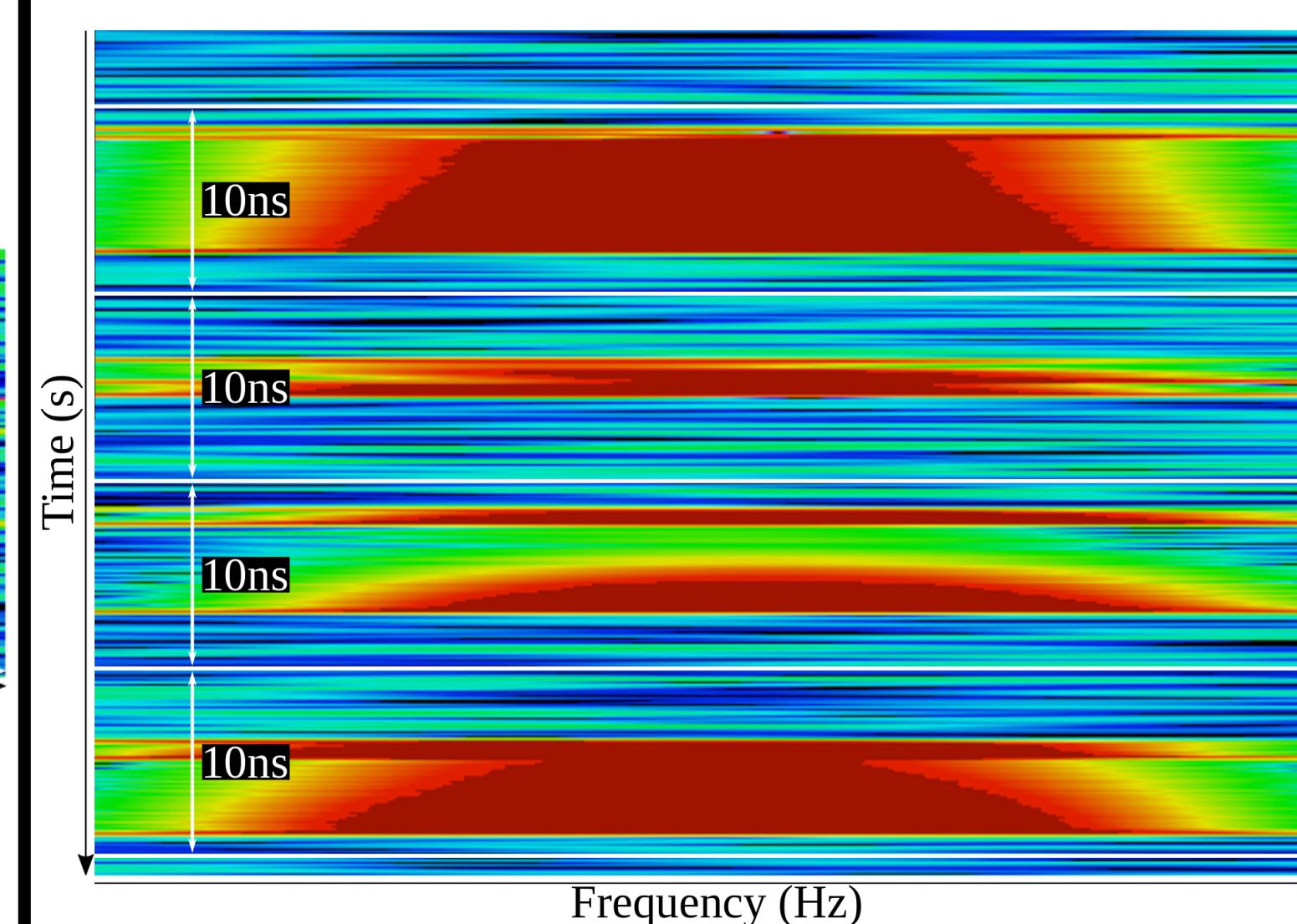
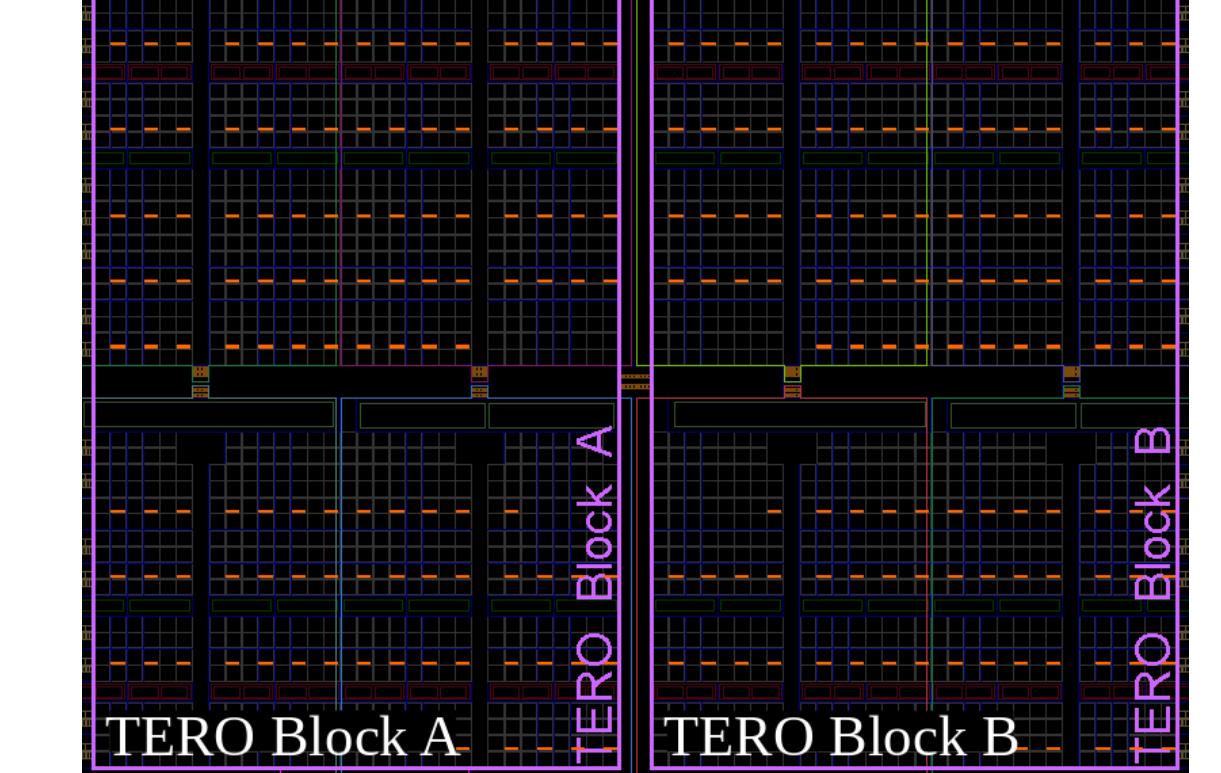


### Two TEROS

oscillating simultaneously



### Full TERO-PUF



## Full TERO-PUF cloning

### Step 1:

$$\begin{aligned} A_1 &\leftrightarrow B_1 \\ A_1 &\leftrightarrow B_2 \end{aligned}$$

### Step 2:

$$\begin{aligned} A_1 &\leftrightarrow B_i \\ A_1 &\leftrightarrow B_2 \end{aligned} \quad \text{for } 3 < i < m$$

### Step 3:

$$\begin{aligned} A_i &\leftrightarrow B_1 \\ A_i &\leftrightarrow B_2 \end{aligned} \quad \text{for } 2 < i < m$$

2m+1 comparisons overall : **linear complexity**

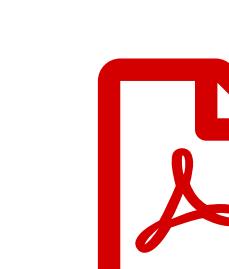
## Conclusion

TERO is **vulnerable to EM analysis**

TERO-PUF can be **fully cloned** with **linear complexity**

Possible **countermeasures**:

- Electromagnetic **shielding**
- **No access** to the "challenge" ( $sel_x$ ) input
- Activation of **all TEROs** for each comparison



Full article available at:  
<https://eprint.iacr.org/2019/300.pdf>

## Code availability

All associated VHDL code is **open source** and **available online** at:  
<https://gitlab.univ-st-etienne.fr/ugo.mureddu/em-analysis-of-transient-effect-ring-oscillator-based-puf>